INFORMATION DISCLOSURE			ATTY, DOCKET NO.	SEI	RIAL NO.			
			07783.0006.CPUS00 09/784,972					
500	PTO-1449		APPLICANTS: Mary Chan-Park					
APR 2 6 2004			FILING DATE: 2/15/2001	GR	OUP: 1756			
- J		U.S	S. PATENT DOCUMENTS					
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILIN	G DATE	
nn)	3,892,568	07/01/1975	Ota et al.	204	477			
PW	4,655,897	04/07/1987	Disanto et al.	359	296			
M	5,177,476	01/05/1993	Disanto et al.	359	296			
m	5,460,688	10/24/1995	Disanto et al	216	67			
W)	5,480,938	Jan 1996	Badesha et al	525	102			
(1/1)	5,872,552	02/16/1999	Gordon II et al.	359	296			
m	5,943,113	Aug 1999	Ishihashi	349	126			
- an	5,967,871	Oct 1999	Kaake et al	65	102			
ino	5,978,062	Nov 1999	Liang et al	349	132			
DAD.	6,067,185	May 2000	Albert et al	204	478	-		
m	6,319,381	Nov 2001	Nemelka	204	486			
no	6,524,153	Feb 2003	Ikeda et al	427	1			
w	6,652,075	Nov 2003	Jacobson	347				
no	2001/0009352	07/26/2001	Moore	313	582			
ND	20020182544	12/05/2002	Chan-Park, et al.	355	402			
		<u> </u>						
	T-"		EIGN PATENT DOCUMENTS					
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY (Inventor)	CLASS	SUBCLASS		LATION	
000	JP 59-034518	Feb 1984	Japan (English abstract included)			YES	NO	
PW	JP 62-099727	May 1987	Japan (English abstract included)					
pro	JP 62-203123	Sep 1987	Japan (English abstract included)					
1)(1)	JP 01-300232	Dec 1989	Japan (English abstract included)				<u> </u>	
MD	JP 02-223936	Sep 1990	Japan (English abstract included)			-	_	
MD	JP 04-113386	Apr 1992	Japan (English abstract included)				-	
- DUD	JP 09-160052	Jun 1997	Japan (English abstract included)					
gro	WO 97/04398	Pub Date 02/06/1997	PCT (Jacobson)				-	

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STATEMENT  O B 2003 22 PTO-1449			ATTY. DOCKET NO.	SI	SERIAL NO.				
			26822-0006	09	09/784,972				
			APPLICANT: Mary Chan-Park, et al.						
	110-1447	FILING DATE: 2/15/01	G	GROUP: 1756					
MADEMIA		U.S	S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING	DATE		
010	*2002/0196525	12/26/2002	Chen et al.	REC	EIVED296				
no	*2002/0018043	02/14/2002	Nakanishi	745	16 2003				
ar	*2002/0188053	12/12/2002	Zang et al.	52	4 74		1		
FOREIGN PATENT DOCUMENTS									
EXAMINER'S	PATENT NO.	DATE	COUNTRY (Inventor)	CLASS	SUBCLASS	TRANSLATION			
INITIALS				1		YES	NO		
DID	*2,340,683	Nat'l Entry Dt 2/14/2001	Canada (Schmidt, F. G.)			Ø			
no	*EP 1195603	Pub Date 04/10/2002	Europe (Kawai)						
DLD	*199 27 359.6	Pub. Date 12/21/00	Germany <sup>1</sup> (Schmidt, F. G.)				⊠		
DLP	*JP 2001 056653	Pub Date 02/27/2001	Japan (Hayakawa) (English abstract included)				⊠		
DÚ	*JP 02284126	Pub Date 11/21/1990	Japan (Oshiro) (English abstract included)				Ø		
no	*WO 00/77571	Pub Date 12/21/00	PCT (Schmidt, F. G.)				☒		
pio	*WO 99/53373	Pub Date 10/21/1999	PCT (Drzaic)						
	OTHER DO	CUMENTS (	Including Author, Title, Date, P	ertinent	Pages, Etc.)				
DLD		*Bryning et al., "Reverse-Emulsion Electrophoretic Display (REED)" SID 98 Digest 1018-1021 (1998)							
OLD	*Inoue, S. et al., TFTs With Four-	*Inoue, S. et al., "High Resolution Microencapsulated Electrophoretic Display (EPD) Driven by Poly-Si TFTs With Four-Level Grayscale" <i>IEEE Transactions on Electron Devices</i> 49(8):1532-1539 (2002)							
PW	*Kazlas, P. et al., "SVGA Microencapsulated Electorphoretic Active Matrix Display for Information Applicances" SID 01 Digest 152-155 (2001)								
W	*Kishi, E et al, "5.1 Development of In-Plane EPD", Canon Research Center, SID Digest p. 24-27 (2000)								
True Marie	LOW LAW DATE CONSIDERED 06/02/2004								

EXAMINER Destruction DATE CONSIDERED U6 02 VVV T

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>&</sup>lt;sup>1</sup> See English counterparts US Patent No. 6,512,626 or Canadian Patent Application No. 2,340,683. Applicant would be happy to obtain a direct translation of the document if desired.

INFORMATION DISCLOSURE STATEMENT PTO-1449			ATTY, DOCKET NO. 26822-0006	52-	SERIAL NO. 09/784,972			
			APPLICANTS: Mary Chan-Park, et al.					
10 8 2003 8	F10-1449	FILING DATE: 2/15/01	GROUP: 1756					
- 15 SE		U.	S. PATENT DOCUMENTS					
EXAMINER'S INITIALS	PATENT NO. DATE		NAME	CLASS	SUBCLASS	FILING DATE		
			RECEIVED					
			DEC 16 2003					
			TC 1700					
			10 1700		<u> </u>			
		FOR	EIGN PATENT DOCUMENTS					
EXAMINER'S	PATENT NO.	DATE	COUNTRY (Inventor)	CLASS	SUBCLASS	YES	NO	
INITIALS					ļ	YES		
							片	
						H		
				<u> </u>				
	OTHER DOO	CUMENTS	(Including Author, Title, Date, Po	ertinent P	iges, Etc.)			
ND	*Matsuda Y. "Newly designed, high resolution, active matrix addressing in plane EPD" IDW 02 EP2-3 1341-1344 (2002)							
DID	*Ota et al. "Developments in Electrophoretic Displays" Proc. of SID 18:243-254 (1977)							
M	*Swanson et al., "High Performance Electrophoretic Displays" SID 00 Digest 29-31 (2000)							
EXAMINER	Dorohlhad	Dern	DATE CONSIDERED O	602	2004			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.